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| 1. Record Nr. | UNINA9910784733103321 |
| Autore | Joy David C. <1943-> |
| Titolo | Monte Carlo modeling for electron microscopy and microanalysis [[electronic resource] /] / David C. Joy |
| Pubbl/distr/stampa | New York, : Oxford University Press, 1995 |
| ISBN | 0-19-773242-9 1-280-53489-3 9786610534890 0-19-535846-5 |
| Descrizione fisica | 1 online resource (225 p.) |
| Collana | Oxford series in optical and imaging sciences ; ; 9 |
| Disciplina | 502/.8/25 |
| Soggetti | Electron microscopy - Computer simulation Electron probe microanalysis - Computer simulation Monte Carlo method |
| Lingua di pubblicazione | Inglese |
| Formato | Materiale a stampa |
| Livello bibliografico | Monografia |
| Note generali | Description based upon print version of record. |
| Nota di bibliografia | Includes bibliographical references. |
| Nota di contenuto | Contents; 1. An Introduction to Monte Carlo Methods; 2. Constructing a Simulation; 3. The Single Scattering Model; 4. The Plural Scattering Model; 5. The Practical Application of Monte Carlo Models; 6. Backscattered Electrons; 7. Charge Collection Microscopy and Cathodoluminescence; 8. Secondary Electrons and Imaging; 9. X-ray Production and Microanalysis; 10. What Next in Monte Carlo Simulations?; References; Index |
| Sommario/riassunto | 1. Preface. 2. An Introduction to Monte Carlo Methods. 3. Constructing a Simulation. 4. The Single Scattering Model. 5. The Plural Scattering Model. 6. Practical Applications of Monte Carlo Models. 7. Backscattered Electrons. 8. Charge Collection and Cathodoluminescence. 9. Secondary Electrons and Imaging. 10. X-Ray Production and Micro-Analysis. 11. What Next in Monte Carlo Simulations? |